

FIS920030146US1 / U.S. Serial No. 10/604,989 Stephen W. Bedell et al. / LJJ "AN ELECTRON MICROSCOPE MAGNIFICATION **STANDARD PROVIDING PRECISE CALIBRATION IN THE MAGNIFICATION** RANGE 5000X-200,000X" 1/5

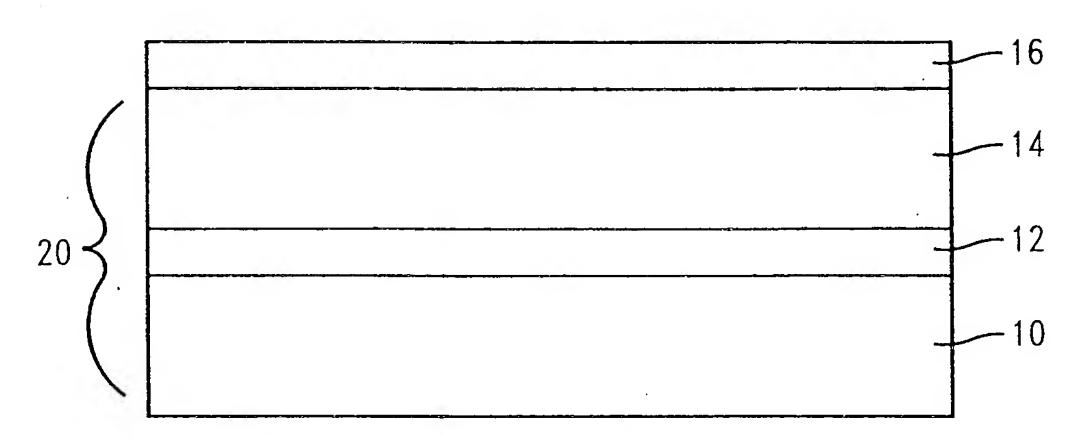


FIG. 1

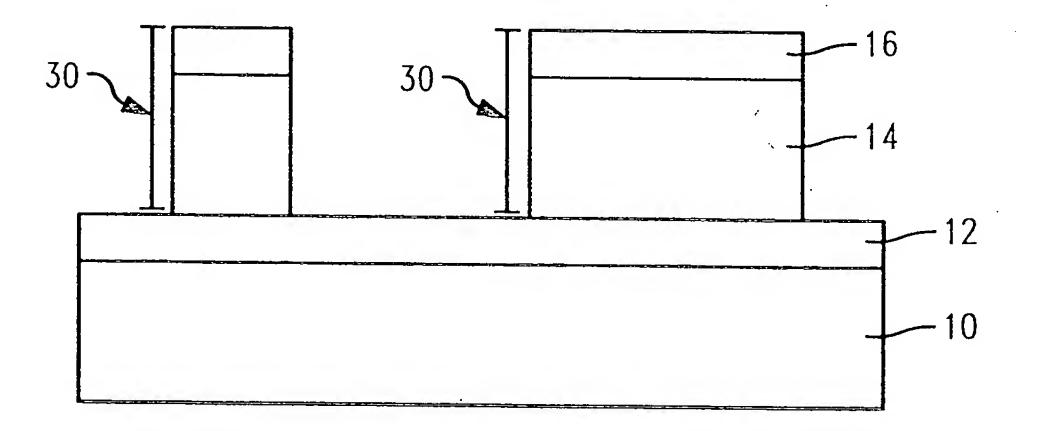


FIG. 2

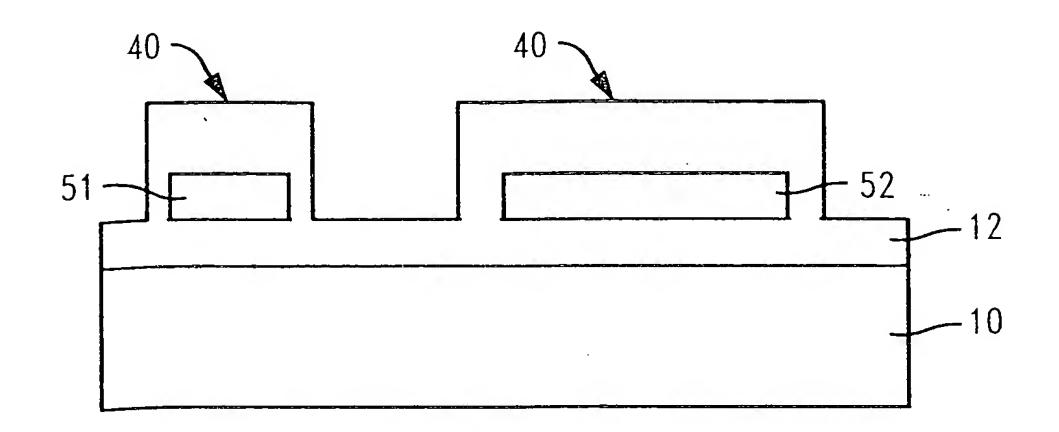
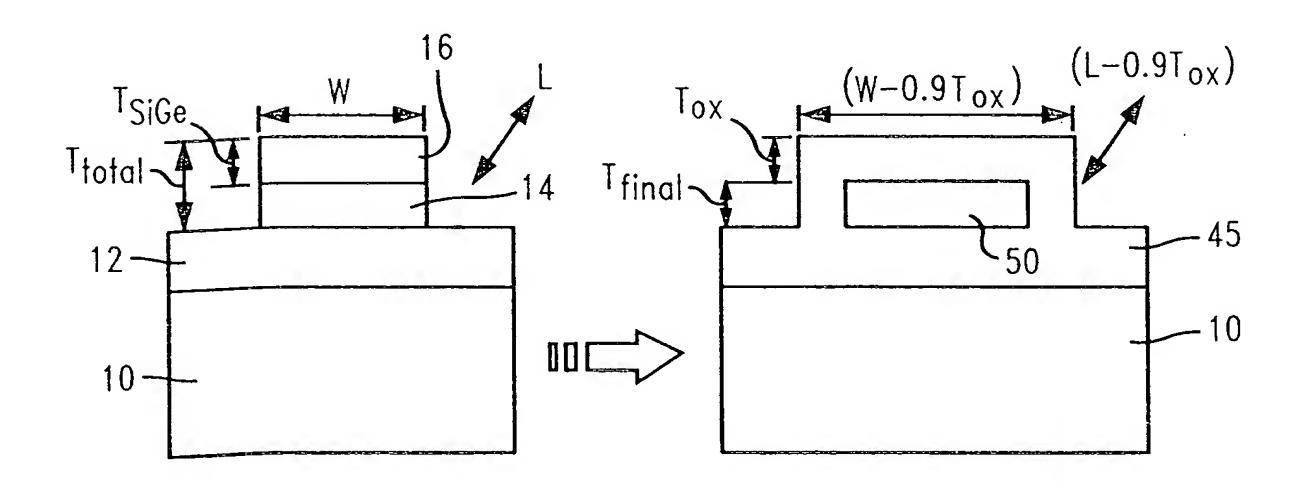
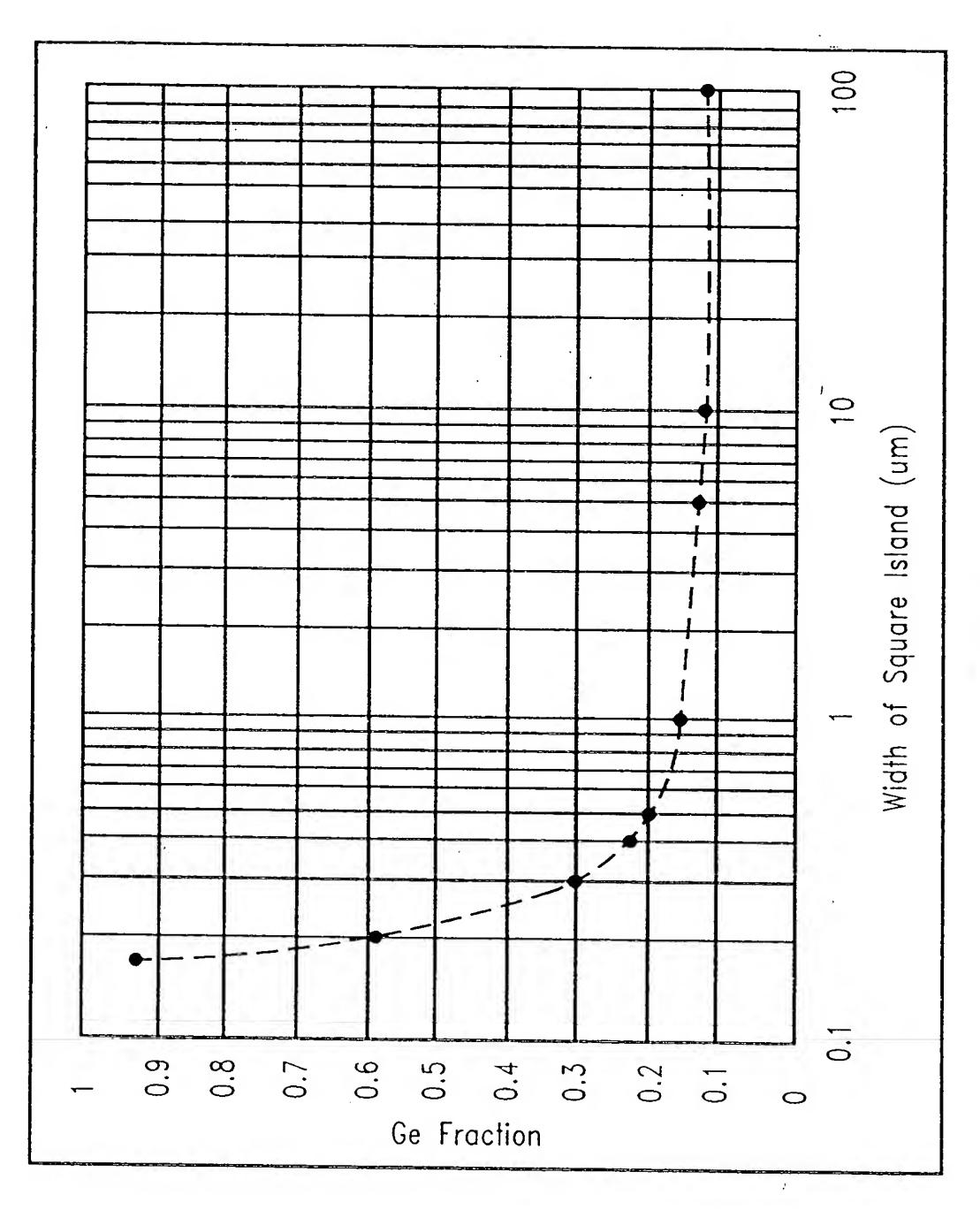


FIG. 3A

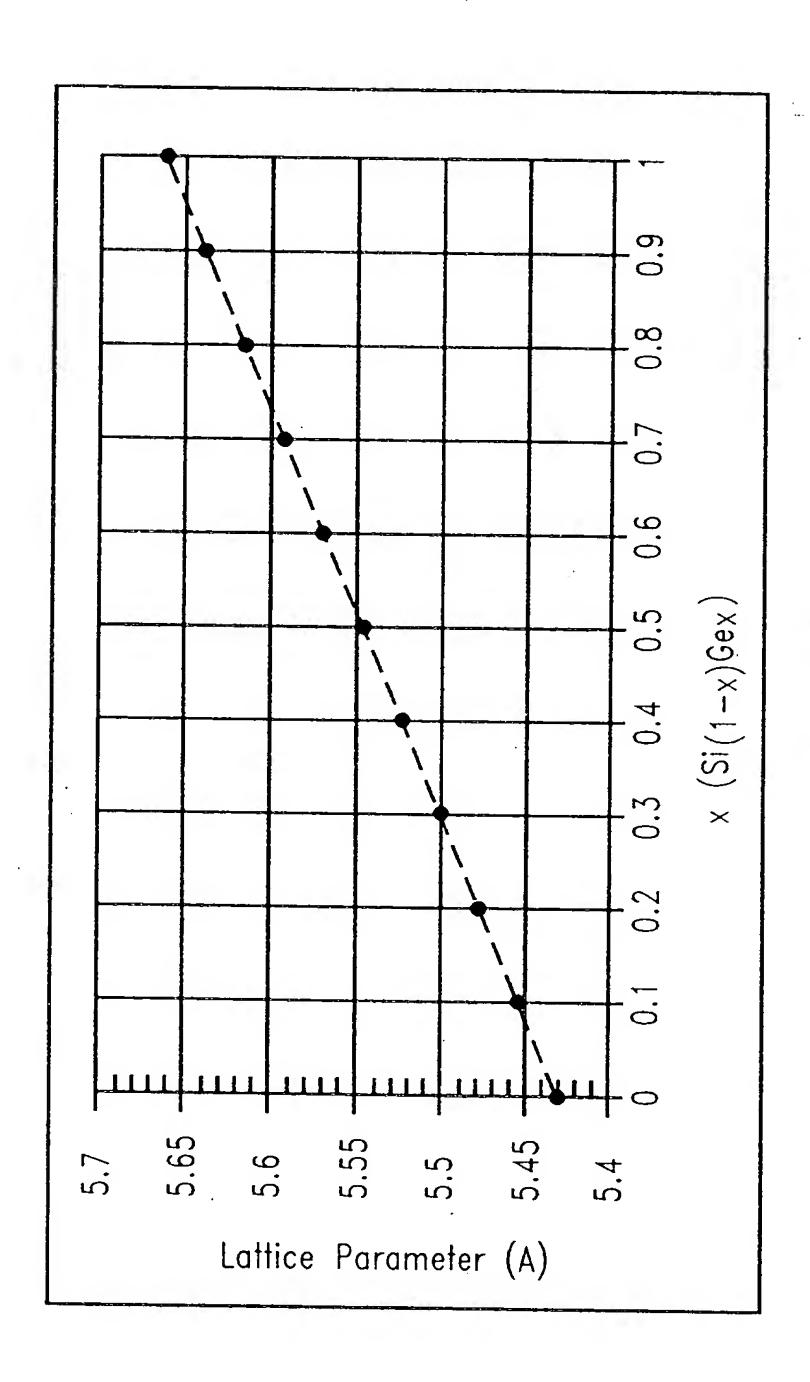


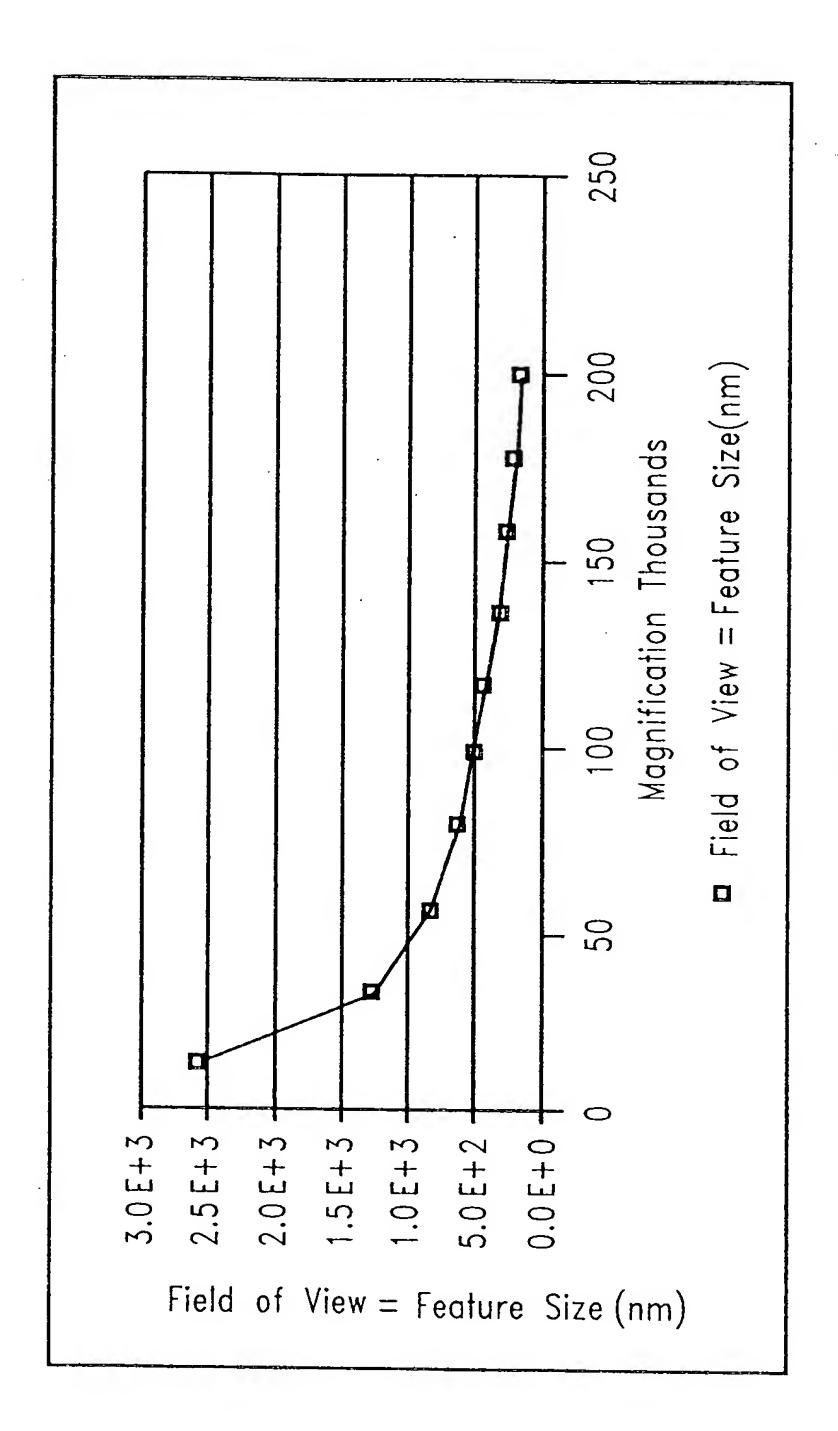
$$X_{SGOI} = \frac{(LWt_{SiGe} \times SiGe)}{(L-0.9t_{Ox})(W-0.9t_{Ox})(t_{Total}-0.45t_{Ox})}$$

FIG. 3B



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